

Search Notes

Application/Control No.

10/616,014

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

LEWIS, JOHN K.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	22	9/15/2005	DB
	288.1		
	55		
	123.1		
	123.15		
29	890.14		
	282		
	237		
228	131		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner